

RELIABILITY REPORT
FOR
MAX4198ExA
PLASTIC ENCAPSULATED DEVICES

April 24, 2003

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Written by



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Conclusion

The MAX4198 successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX4198 low-power, Rail-to-Rail[®] differential amplifiers is deal for single-supply applications that benefit from a low 0.01% gain error. The MAX4198 is factory trimmed to a fixed gain of +1V/V. Capable of operating from a single +2.7V to +7.5V supply or from dual $\pm 1.35V$ to $\pm 3.75V$ supplies, it consumes only 42 μA while achieving -3dB bandwidths of. This amplifier features a shutdown mode that reduces the supply current to 6.5 μA .

The MAX4198 can drive 5k Ω loads to within 100mV from each rail. The standard differential amplifier configurations provide common-mode rejection of 90dB. The input common-mode voltage range for the MAX4198 extends 100mV Beyond-the-Rails[™].

The MAX4198 is offered in a space-saving 8-pin μMAX package

B. Absolute Maximum Ratings

<u>Item</u>	<u>Rating</u>
Supply Voltage (VCC to VEE)	+8V
All Other Pins to GND	(VEE - 0.3V) to (VCC + 0.3V)
Output Short Circuit Duration (to VCC or VEE)	Continuous
Operating Temperature Range	-40°C to +85°C
Junction Temperature	+150°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (soldering, 10sec)	+300°C
Continuous Power Dissipation (TA = +70°C)	
8-Pin SO	471mW
8-Pin μMAX	330mW
Derates above +70°C	
8-Pin SO	9.09mW/°C
8-Pin μMAX	4.1mW/°C

II. Manufacturing Information

A. Description/Function:	Micropower, Single-Supply, Rail-to-Rail Precision Differential Amplifiers
B. Process:	S12 (Standard 1.2 micron silicon gate CMOS)
C. Number of Device Transistors:	250
D. Fabrication Location:	Oregon, USA
E. Assembly Location:	Philippines, Thailand or Malaysia
F. Date of Initial Production:	April, 1999

III. Packaging Information

	8-Pin NSO	8-Pin uMAX
A. Package Type:	8-Pin NSO	8-Pin uMAX
B. Lead Frame:	Copper	Copper
C. Lead Finish:	Solder Plate	Solder Plate
D. Die Attach:	Silver-filled Epoxy	Silver-filled Epoxy
E. Bondwire:	Gold (1.3 mil dia.)	Gold (1.3 mil dia.)
F. Mold Material:	Epoxy with silica filler	Epoxy with silica filler
G. Assembly Diagram:	# 05-3001-0104	# 05-3001-0105
H. Flammability Rating:	Class UL94-V0	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard JESD22-112:	Level 1	Level 1

IV. Die Information

A. Dimensions:	58 x 80 mils
B. Passivation:	Si ₃ N ₄ /SiO ₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Aluminum/Si (Si = 1%)
D. Backside Metallization:	None
E. Minimum Metal Width:	1.2 microns (as drawn)
F. Minimum Metal Spacing:	1.2 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO ₂
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

- A. Quality Assurance Contacts: Jim Pedicord (Reliability Lab Manager)
Bryan Preeshl (Executive Director)
Kenneth Huening (Vice President)
- B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.
- C. Observed Outgoing Defect Rate: < 50 ppm
- D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in **Table 1**. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4389 \times 80 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

▲
Temperature Acceleration factor assuming an activation energy of 0.8eV

$$\lambda = 13.57 \times 10^{-9}$$

$$\lambda = 13.57 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

This low failure rate represents data collected from Maxim's reliability monitor program. In addition to routine production Burn-In, Maxim pulls a sample from every fabrication process three times per week and subjects it to an extended Burn-In prior to shipment to ensure its reliability. The reliability control level for each lot to be shipped as standard product is 59 F.I.T. at a 60% confidence level, which equates to 3 failures in an 80 piece sample. Maxim performs failure analysis on any lot that exceeds this reliability control level. Attached Burn-In Schematic (Spec. # 06-5323) shows the static Burn-In circuit. Maxim also performs quarterly 1000 hour life test monitors. This data is published in the Product Reliability Report (**RR-1M**).

B. Moisture Resistance Tests

Maxim pulls pressure pot samples from every assembly process three times per week. Each lot sample must meet an LTPD = 20 or less before shipment as standard product. Additionally, the industry standard 85°C/85%RH testing is done per generic device/package family once a quarter.

C. E.S.D. and Latch-Up Testing

The OP58 die type has been found to have all pins able to withstand a transient pulse of $\pm 2000\text{V}$, per Mil-Std-883 Method 3015 (reference attached ESD Test Circuit). Latch-Up testing has shown that this device withstands a current of $\pm 250\text{mA}$.

Table 1
Reliability Evaluation Test Results

MAX4198ExA

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	PACKAGE	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)					
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality		80	0
Moisture Testing (Note 2)					
Pressure Pot	Ta = 121°C P = 15 psi. RH= 100% Time = 168hrs.	DC Parameters & functionality	SO uMAX	77 77	0 0
85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality		77	0
Mechanical Stress (Note 2)					
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters		77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.

Note 2: Generic Package/Process data

Attachment #1

TABLE II. Pin combination to be tested. 1/ 2/

	Terminal A (Each pin individually connected to terminal A with the other floating)	Terminal B (The common combination of all like-named pins connected to terminal B)
1.	All pins except V_{PS1} 3/	All V_{PS1} pins
2.	All input and output pins	All other input-output pins

1/ Table II is restated in narrative form in 3.4 below.

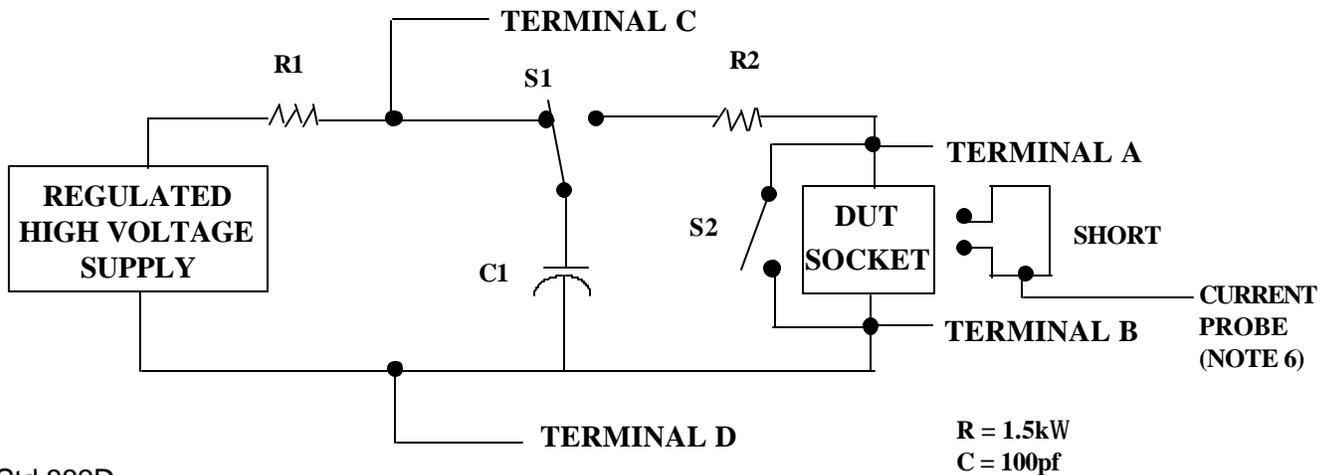
2/ No connects are not to be tested.

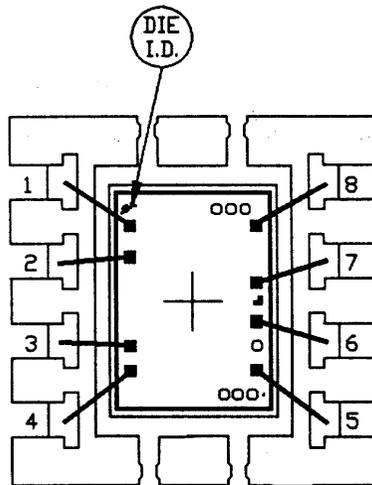
3/ Repeat pin combination I for each named Power supply and for ground

(e.g., where V_{PS1} is V_{DD} , V_{CC} , V_{SS} , V_{BB} , GND, $+V_S$, $-V_S$, V_{REF} , etc).

3.4 Pin combinations to be tested.

- a. Each pin individually connected to terminal A with respect to the device ground pin(s) connected to terminal B. All pins except the one being tested and the ground pin(s) shall be open.
- b. Each pin individually connected to terminal A with respect to each different set of a combination of all named power supply pins (e.g., V_{SS1} , or V_{SS2} or V_{SS3} or V_{CC1} , or V_{CC2}) connected to terminal B. All pins except the one being tested and the power supply pin or set of pins shall be open.
- c. Each input and each output individually connected to terminal A with respect to a combination of all the other input and output pins connected to terminal B. All pins except the input or output pin being tested and the combination of all the other input and output pins shall be open.



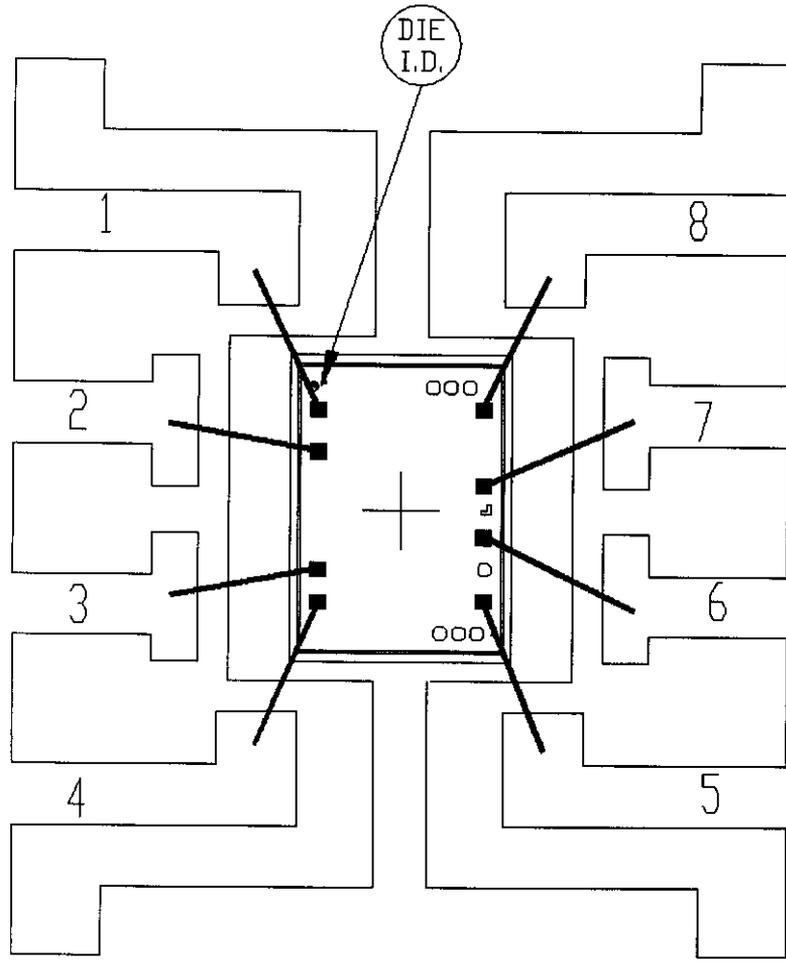


PKG. CODE:	U8-1	
CAV./PAD SIZE:	68X94	PKG. DESIGN

APPROVALS

DATE

MAXIM	
BUILDSHEET NUMBER:	REV.:
05-3001-0105	A



PKG.CODE: S8-2

CAV./PAD SIZE: 90 X 90

APPROVALS

DATE

MAXIM

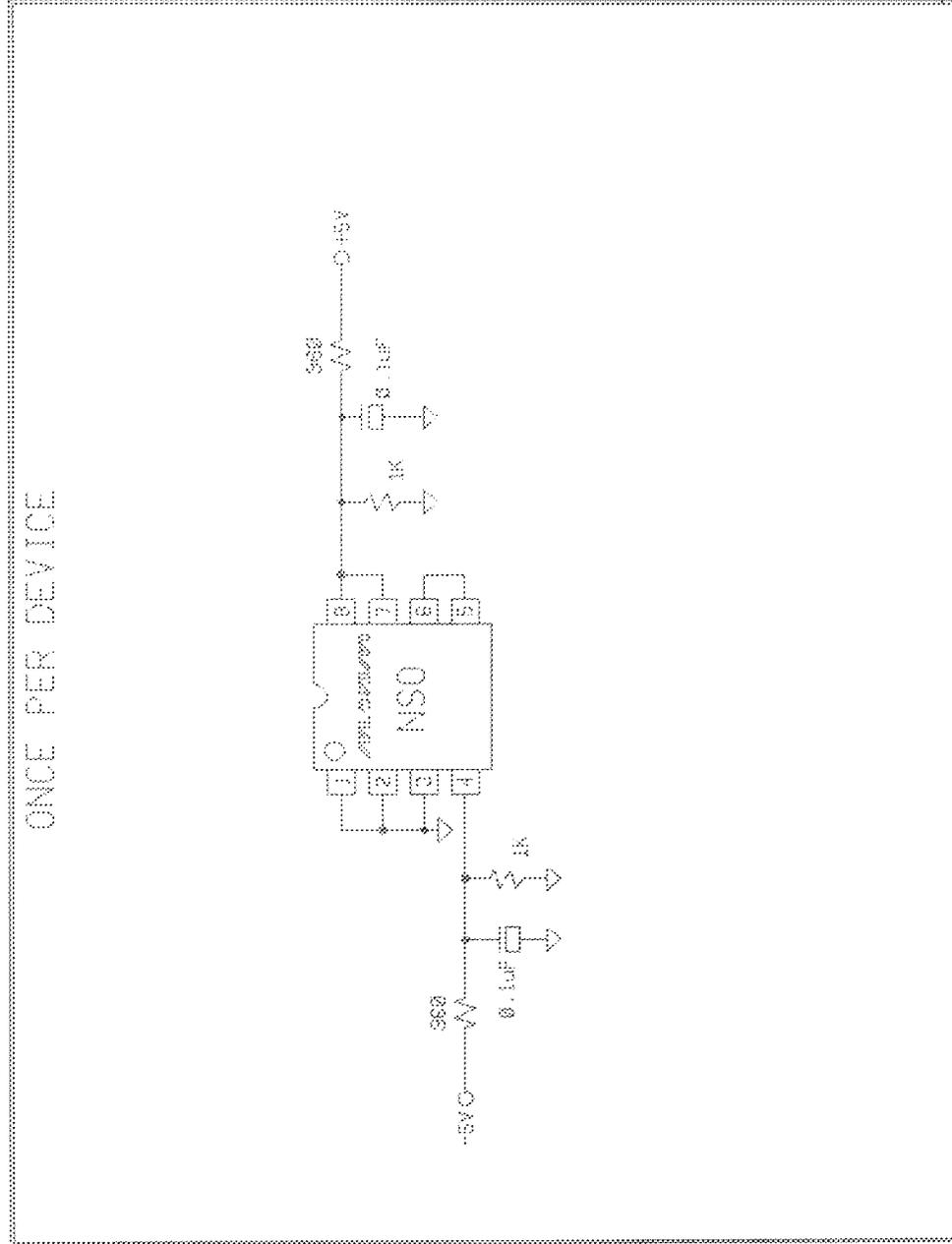
PKG.
DESIGN

BUILDSHEET NUMBER:
05-3001-0104

REV.:
A

ONCE PER BOARD

ONCE PER DEVICE



--- STADY STATE LIFE TEST IS PER MIL-STD-883 METHOD 1005
 --- BURN-IN IS PER MIL-STD-883 METHOD 1015. COND. B

NOTES:

1. TEMPERATURE: 125C OR EQUIVALENT
2. TIME: 160 HOURS MIN. OR EQUIVALENT
3. ALL COMPONENTS AND MATERIAL MUST STAND 150C CONTINUOUS
4. APPROVED FOR EXJ COMMERCIAL EXJ HR/883

SPEC. NO. 06-5323 REV: A

DATE: 11/14/97

DRAWN BY:

MAXIM BURN-IN SCHEMATIC

DEVICE TYPE(S):

MAX4195/6/7/8/9